



## APPENDIX B

### Z86017/Z16017 ELECTRICAL CHARACTERISTICS AND TIMING

#### B1.1 ABSOLUTE MAXIMUM RATINGS

| Parameter              | Symbol     | Unit | Min. Value | Max. Value     |
|------------------------|------------|------|------------|----------------|
| Supply Voltage         | $V_{DD}$   | V    | -0.5       | 7.0            |
| Input Voltage          | $V_I$      | V    | -0.5       | $V_{DD} + 0.5$ |
| Output Voltage         | $V_O$      | V    | -0.5       | $V_{DD} + 0.5$ |
| Storage Temperature    | $T_{STG}$  | C    | -40        | +125           |
| Temperature Under Bias | $T_{BIAS}$ | C    | -25        | +85            |

#### B1.2 DC ELECTRICAL CHARACTERISTICS

$V_{CC} = 3.3V \pm 10\%$

| Sym.      | Parameter                | $T_A = 0^{\circ}C \text{ to } +70^{\circ}C$ |              | Typical<br>at 25°C | Units   | Conditions              | Notes |
|-----------|--------------------------|---------------------------------------------|--------------|--------------------|---------|-------------------------|-------|
|           |                          | Min.                                        | Max.         |                    |         |                         |       |
| $V_{IH}$  | Input High Voltage       | $0.7 V_{CC}$                                | $V_{CC}$     |                    | V       |                         |       |
| $V_{IL}$  | Input Low Voltage        | -0.3                                        | $0.1 V_{CC}$ |                    | V       |                         |       |
| $V_{OH}$  | Output High Voltage      | 1.8                                         |              |                    | V       | $I_{OH} = 4 \text{ mA}$ |       |
| $V_{OH}$  | Output High Voltage      | $V_{CC} - 100 \text{ mV}$                   |              |                    | V       | $I_{OH} = 100 \mu A$    |       |
| $V_{OL}$  | Output Low Voltage       |                                             | 0.4          |                    | V       | $I_{OL} = 4 \text{ mA}$ |       |
| $V_{RH}$  | Reset Input High Voltage | $0.8 V_{CC}$                                | $V_{CC}$     |                    | V       |                         |       |
| $V_{RI}$  | Reset Input Low Voltage  | -0.3                                        | $0.1 V_{CC}$ |                    | V       |                         |       |
| $I_{IL}$  | Input Leakage            | -2                                          | 2            |                    | $\mu A$ | Test at 0V, $V_{CC}$    |       |
| $I_{OL}$  | Output Leakage           | -2                                          | 2            |                    | $\mu A$ | Test at 0V, $V_{CC}$    |       |
| $I_{IR}$  | Reset Input Current      |                                             | -80          |                    | $\mu A$ | $V_{RL} = 0V$           |       |
| $I_{CC}$  | Supply Current           |                                             | 4            | 3                  | mA      | @ 20 MHz                | [1]   |
| $I_{CC1}$ | Standby Current          |                                             | 300          | 250                | $\mu A$ |                         | [2]   |

##### Notes:

[1] All inputs driven to 0V,  $V_{CC}$  and outputs floating.

[2] EN\_Pads Bit Set, PC\_MCLK = 0, EE\_SK=0



## B1.2 DC ELECTRICAL CHARACTERISTICS (Continued)

 $V_{CC} = 5.0V \pm 10\%$ 

| Sym.      | Parameter                | $T_A = 0^\circ C \text{ to } +70^\circ C$ |          | Typical<br>at $25^\circ C$ | Units   | Conditions               | Notes |
|-----------|--------------------------|-------------------------------------------|----------|----------------------------|---------|--------------------------|-------|
|           |                          | Min.                                      | Max.     |                            |         |                          |       |
| $V_{IH}$  | Input High Voltage       | 2.0                                       | $V_{CC}$ |                            | V       |                          |       |
| $V_{IL}$  | Input Low Voltage        | -0.3                                      | 0.8      |                            | V       |                          |       |
| $V_{OH}$  | Output High Voltage      | 2.4                                       |          |                            | V       | $I_{OH} = -6 \text{ mA}$ |       |
| $V_{OH}$  | Output High Voltage      | $V_{CC} - 100 \text{ mV}$                 |          |                            | V       | $I_{OH} = 100 \mu A$     |       |
| $V_{OL}$  | Output Low Voltage       |                                           | 0.4      |                            | V       | $I_{OL} = 6 \text{ mA}$  |       |
| $V_{RH}$  | Reset Input High Voltage | 3.8                                       | $V_{CC}$ |                            | V       |                          |       |
| $V_{RI}$  | Reset Input Low Voltage  | -0.3                                      | 0.8      |                            | V       |                          |       |
| $I_{IL}$  | Input Leakage            | -2                                        | 2        |                            | $\mu A$ | Test at 0V, $V_{CC}$     |       |
| $I_{OL}$  | Output Leakage           | -2                                        | 2        |                            | $\mu A$ | Test at 0V, $V_{CC}$     |       |
| $I_{IR}$  | Reset Input Current      |                                           | -80      |                            | $\mu A$ | $V_{RL} = 0V$            |       |
| $I_{CC}$  | Supply Current           |                                           | 5        | 4                          | mA      | @ 20 MHz                 | [1]   |
| $I_{CC1}$ | Standby Current          |                                           | 350      | 300                        | $\mu A$ |                          | [2]   |

### Notes:

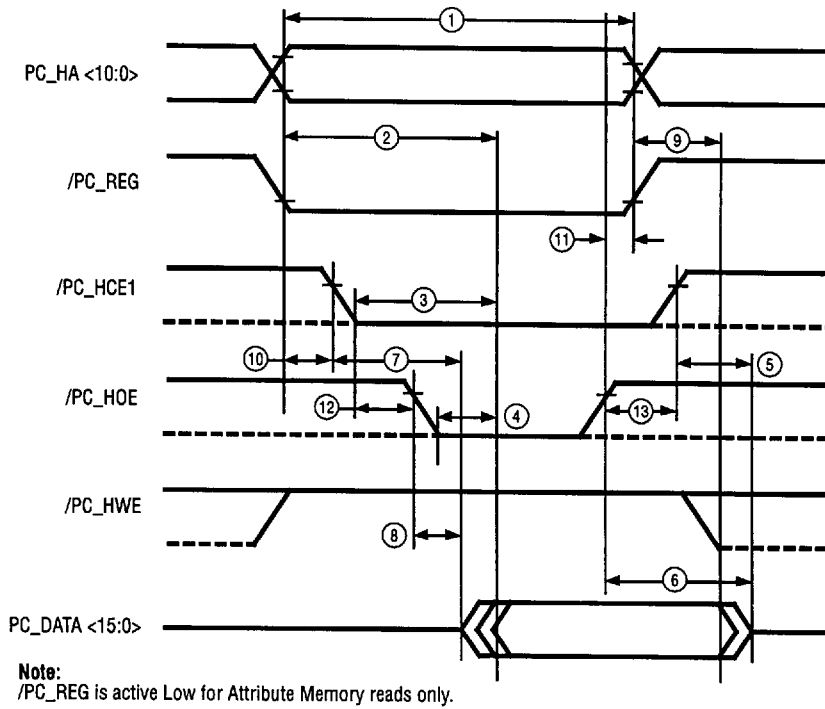
[1] All inputs driven to 0V, or  $V_{CC}$  and outputs floating.

[2] EN\_Pads bit set, PC\_MCLK = 0, EE\_SK = 0

## B1.3 INTERNAL ATTRIBUTE MEMORY TIMING

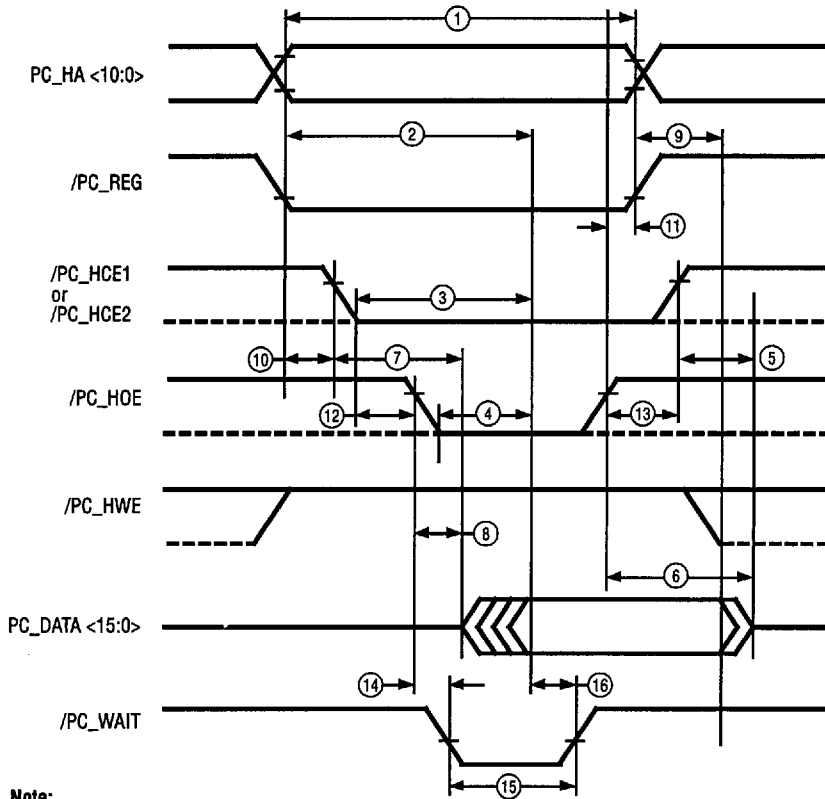
(Speed Version: 300 ns)

| No. | Symbol | Parameter                      | Min. | Max. | Units   |
|-----|--------|--------------------------------|------|------|---------|
| 1   | TcR    | Read Cycle Time                | 300  |      | ns      |
| 2   | TaA    | Address Access Time            |      | 300  | ns      |
| 3   | TaCE   | Card Enable Time               |      | 300  | ns      |
| 4   | TaOE   | Output Enable Access Time      |      | 150  | ns      |
| 5   | TdisCE | Output Disable Time from CE    |      | 100  | ns      |
| 6   | TdisOE | Output Disable Time from OE    |      | 100  | ns      |
| 7   | TenCE  | Output Enable Time from CE     | 5    |      | ns      |
| 8   | TenOE  | Output Enable Time from OE     | 5    |      | ns      |
| 9   | TvA    | Data Valid from Address Change | 0    |      | ns      |
| 10  | TsuA   | Address Setup Time             | 30   |      | ns      |
| 11  | ThA    | Address Hold Time              | 20   |      | ns      |
| 12  | TsuCE  | Card Enable Setup Time         | 0    |      | ns      |
| 13  | ThCE   | Card Enable Hold Time          | 20   |      | ns      |
| 14  | TvWToe | Wait Valid from OE             |      | 35   | ns      |
| 15  | TwWT   | Wait Pulse Width               |      | 12   | $\mu s$ |
| 16  | TvWT   | Data Setup for Wait Released   | 0    |      | ns      |



**Figure B1-1. PCMCIA Read Memory Timing, No Wait States**

### B1.3 INTERNAL ATTRIBUTE MEMORY TIMING (Continued)



**Note:**

/PC\_REG is active Low for Attribute Memory reads only.

**Figure B1-2. PCMCIA Read Memory Timing, Wait State Enabled**

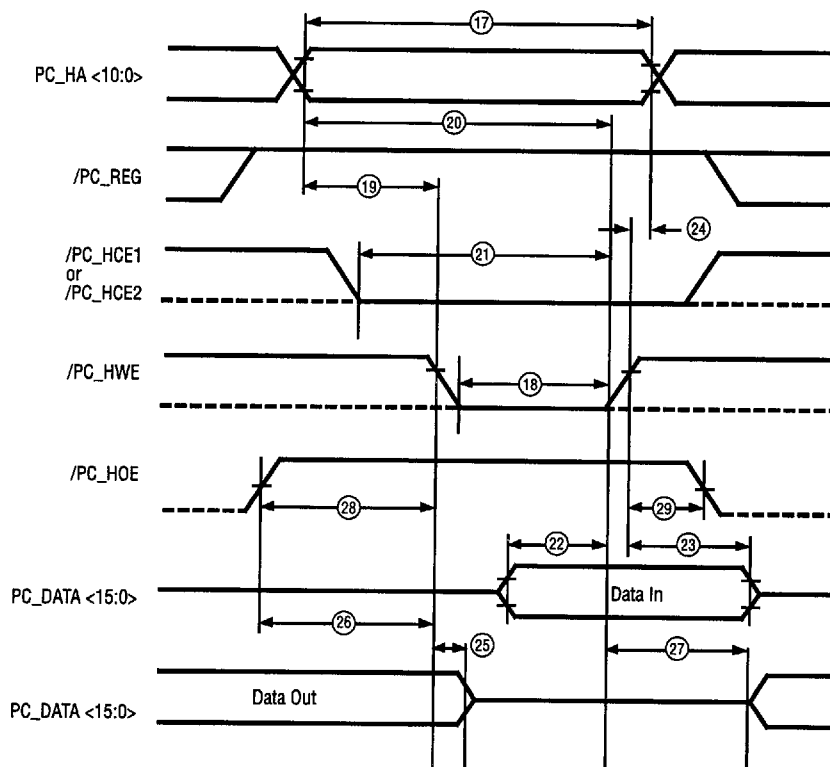


## B1.4 PCMCIA MEMORY WRITE TIMING

| No. | Symbol  | Parameter                     | 200 ns |      | 150 ns |      | 100 ns |      | Units |
|-----|---------|-------------------------------|--------|------|--------|------|--------|------|-------|
|     |         |                               | Min.   | Max. | Min.   | Max. | Min.   | Max. |       |
| 17  | TcW     | Write Cycle Time              | 200    |      | 150    |      | 100    |      | ns    |
| 18  | TwWE    | Write Pulse Width             | 120    |      | 80     |      | 60     |      | ns    |
| 19  | TsuA    | Address Setup Time            | 20     |      | 20     |      | 10     |      | ns    |
| 20  | TsuAwe  | Address Setup Time for WE     | 140    |      | 100    |      | 70     |      | ns    |
| 21  | TsuCwe  | Card Enable Setup Time for WE | 140    |      | 100    |      | 70     |      | ns    |
| 22  | TsuDwe  | Data Setup Time for WE        | 60     |      | 50     |      | 40     |      | ns    |
| 23  | ThD     | Data Hold Time                | 30     |      | 20     |      | 15     |      | ns    |
| 24  | TrecWE  | Write Recover Time            | 30     |      | 20     |      | 15     |      | ns    |
| 25  | TdisOwe | Output Disable Time from WE   |        | 90   |        | 75   |        | 50   | ns    |
| 26  | TdisOE  | Output Disable Time from OE   |        | 90   |        | 75   |        | 50   | ns    |
| 27  | TenWE   | Output Enable Time from WE    | 5      |      | 5      |      | 5      |      | ns    |
| 28  | TsuCwe  | Output Enable Setup from WE   | 10     |      | 10     |      | 10     |      | ns    |
| 29  | ThCwe   | Card Enable Hold from WE      | 10     |      | 10     |      | 10     |      | ns    |
| 30  | TsuCE   | Card Enable Setup Time        | 0      |      | 0      |      | 0      |      | ns    |
| 31  | ThCE    | Card Enable Hold Time         | 20     |      | 20     |      | 15     |      | ns    |
| 32  | TvWTwe  | Wait Valid from WE            |        | 35   |        | 35   |        | 35   | ns    |
| 33  | TwWT    | Wait Pulse Width              |        | 12   |        | 12   |        | 12   | μs    |
| 34  | TvWT    | WE High from Wait Released    | 0      |      | 0      |      | 0      |      | ns    |

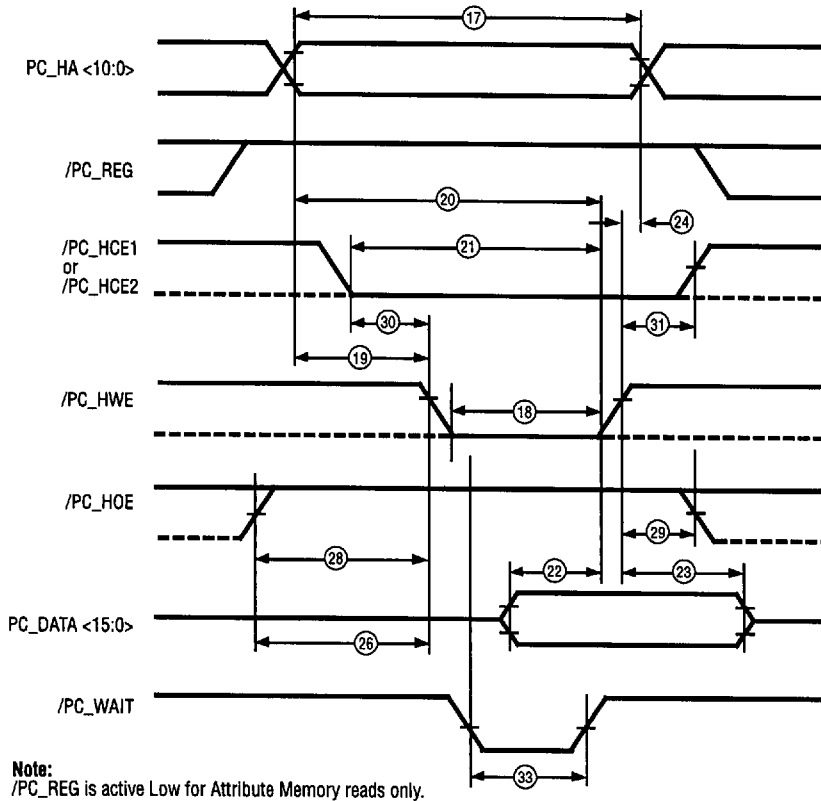


### B1.3 PCMCIA MEMORY WRITE TIMING (Continued)



**Note:** PC\_REG is active Low for Attribute Memory reads only.

**Figure B1-3. PCMCIA Write Memory Timing,  
No Wait States**



**Figure B1-4. PCMCIA Write Memory Timing,  
Wait State Enabled**

## B1.5 I/O READ TIMING SPECIFICATION

| No. | Symbol    | Parameter                      | Min. | Max. | Units |
|-----|-----------|--------------------------------|------|------|-------|
| 35  | TdIORD    | Data Delay After IORD          | 100  |      | ns    |
| 36  | ThIORD    | Data Hold Following IORD       | 0    |      | ns    |
| 37  | twIORD    | IORD Width Time                | 165  |      | ns    |
| 38  | TsuAiord  | Address Setup Before IORD      | 70   |      | ns    |
| 39  | ThAiord   | Address Hold Following IORD    | 20   |      | ns    |
| 40  | TsuCEiord | CE Setup Before IORD           | 5    |      | ns    |
| 41  | ThCEiord  | CE Hold Following IORD         | 20   |      | ns    |
| 42  | TsuRGiord | REG Setup Before IORD          | 5    |      | ns    |
| 43  | ThRGiord  | REG Hold Following IORD        | 0    |      | ns    |
| 44  | TdIPKiord | INPACK Delay to IORD           | 0    | 45   | ns    |
| 45  | TdIPKiord | INPACK Delay from IORD         |      | 45   | ns    |
| 46  | TdIOISad  | IOIS16 Delay from Address      |      | 35   | ns    |
| 47  | TdIOISadr | IOIS16 Delay Rise from Address |      | 35   | ns    |
| 48  | TdWiord   | Wait Delay from IORD           |      | 35   | ns    |
| 49  | TdWTr     | Data Delay from Wait Rising    |      | 35   | ns    |
| 50  | TwWT      | Wait Width Time                |      | 12   | μs    |





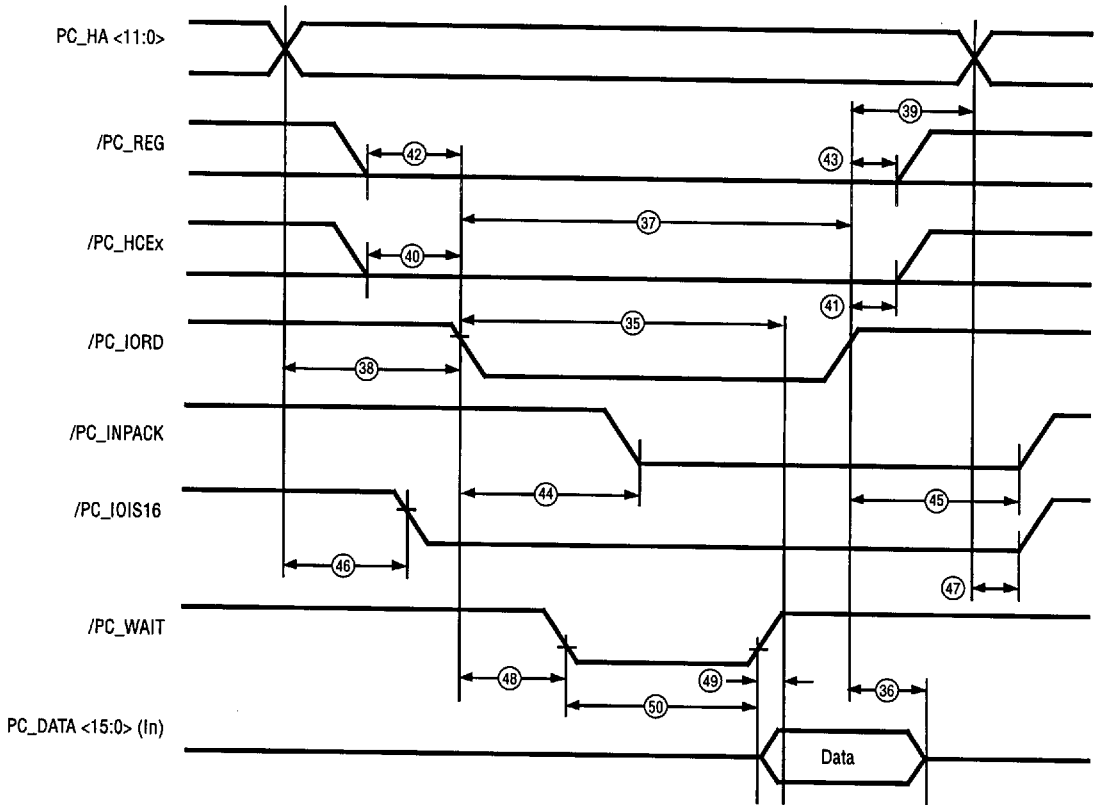


Figure B1-5. I/O Read Timing

## B1.6 I/O WRITE TIMING SPECIFICATION

| No. | Symbol     | Parameter                         | Min. | Max. | Units |
|-----|------------|-----------------------------------|------|------|-------|
| 51  | TsuIOWR    | Data Setup before IOWR            | 60   |      | ns    |
| 52  | ThIOWR     | Data Hold after IOWR              | 30   |      | ns    |
| 53  | TwIOWR     | IOWR Width Time                   | 165  |      | ns    |
| 54  | TsuAiowr   | Address Setup to IOWR             | 70   |      | ns    |
| 55  | ThAiowr    | Address Hold after IOWR           | 20   |      | ns    |
| 56  | TsuCEiowr  | CE Setup before IOWR              | 5    |      | ns    |
| 57  | ThCEiowr   | CE Hold after IOWR                | 20   |      | ns    |
| 58  | TsuRGiowr  | REG Setup before IOWR             | 5    |      | ns    |
| 59  | ThRGiowr   | REG Hold after IOWR               | 0    |      | ns    |
| 60  | TdIOISadr  | IOIS16 Delay Falling from Address |      | 35   | ns    |
| 61  | TIdIOISadr | IOIS16 delay Rising from Address  |      | 35   | ns    |
| 62  | TdWTiowr   | Wait Delay Falling from IOWR      |      | 35   | ns    |
| 63  | TwWT       | Wait Width Timing                 |      | 12   | µs    |

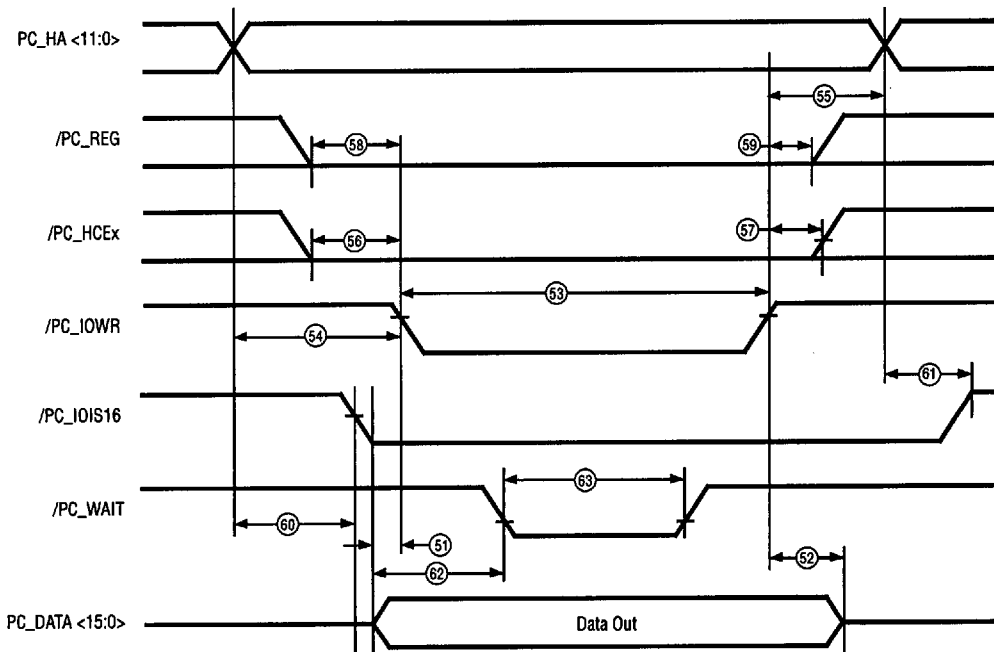


Figure B1-6. I/O Write Timing

## B1.7 SKEW TIMING BETWEEN PCMCIA AND ATA/IDE OR PERIPHERAL BUS

| No. | Symbol  | Parameter     | Min. | Max. | Units |
|-----|---------|---------------|------|------|-------|
| 64  | TskADR  | Address Skew  | 0    | 25   | ns    |
| 65  | TskI/Of | I/O Fall Skew | 0    | 25   | ns    |
| 66  | TskI/Or | I/O Rise Skew | 0    | 25   | ns    |
| 67  | TskMEMf | Mem Fall Skew | 0    | 25   | ns    |
| 68  | TskMEMr | Mem Rise Skew | 0    | 25   | ns    |

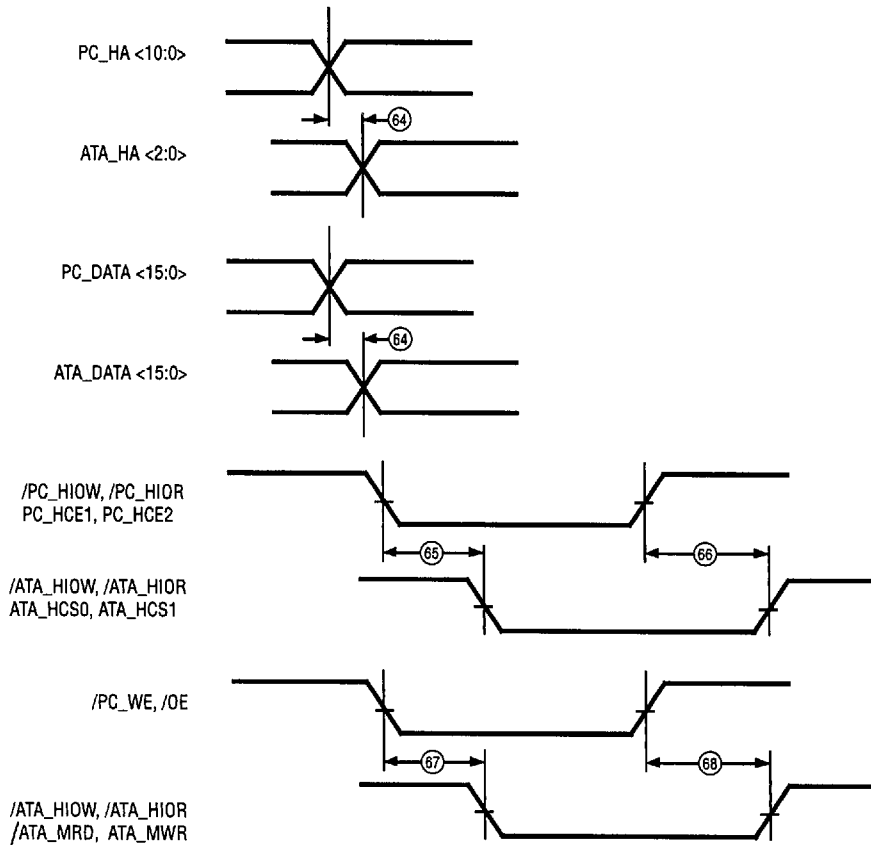


Figure B1-7. Skew Timing Between PCMCIA and ATA/IDE or Peripheral Bus

## B1.8 017 DEVICE SLEW DELAY

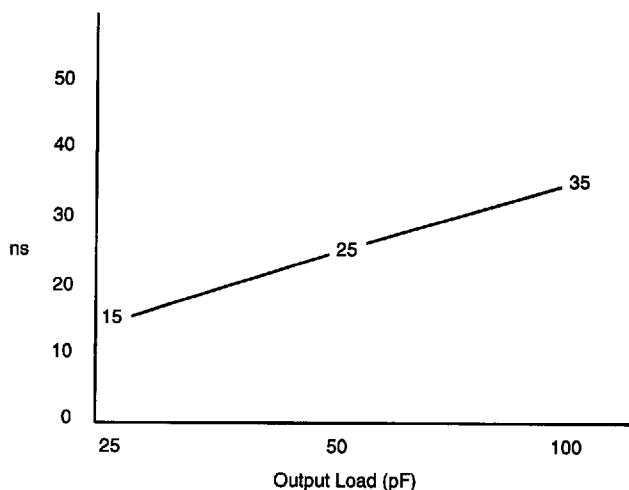


Figure B1-8. 017 Slew Delay Derating Curve (Typical)

## B1.9 SERIAL INTERFACE TIMING

| No. | Symbol  | Parameter              | Min. | Max. | Units |
|-----|---------|------------------------|------|------|-------|
| 69  | TpMCKin | Master Clock In Period | 50   |      | ns    |
| 70  | TsuCS   | CS Setup to CLK time   | 25   |      | ns    |
| 71  | ThCS    | CS Hold after CLK      | 0    |      | ns    |
| 72  | ThDout  | Data Hold Time         | 10   |      | ns    |
| 73  | TsuDout | Data Setup Time        | 25   |      | ns    |
| 74  | ThDin   | Data Hold Time         | 0    |      | ns    |
| 75  | TsuDin  | Data Setup Time        | 25   |      | ns    |
| 76  | TpCKw   | Clock Period, Master   | 200  |      | ns    |
| 77  | TpCKs   | Clock Period, Slave    | 200  |      | ns    |



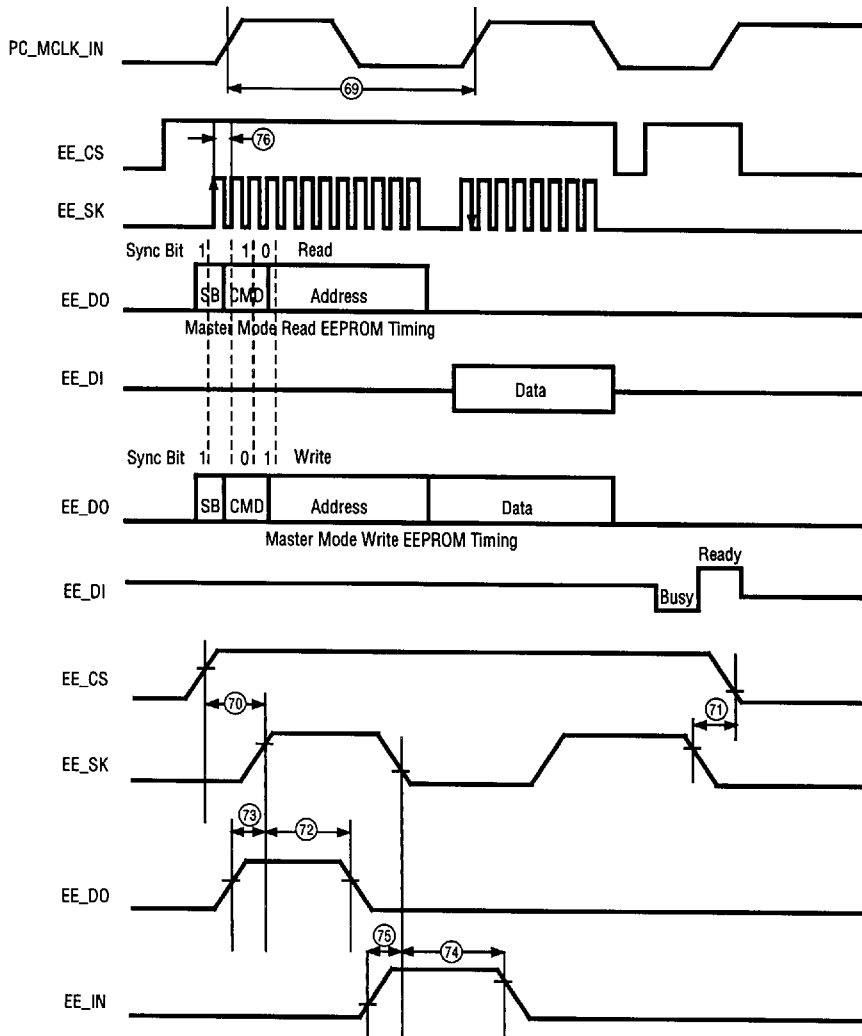


Figure B1-9. Master Mode Read EEPROM Timing

## B1.9 SERIAL INTERFACE TIMING (Continued)

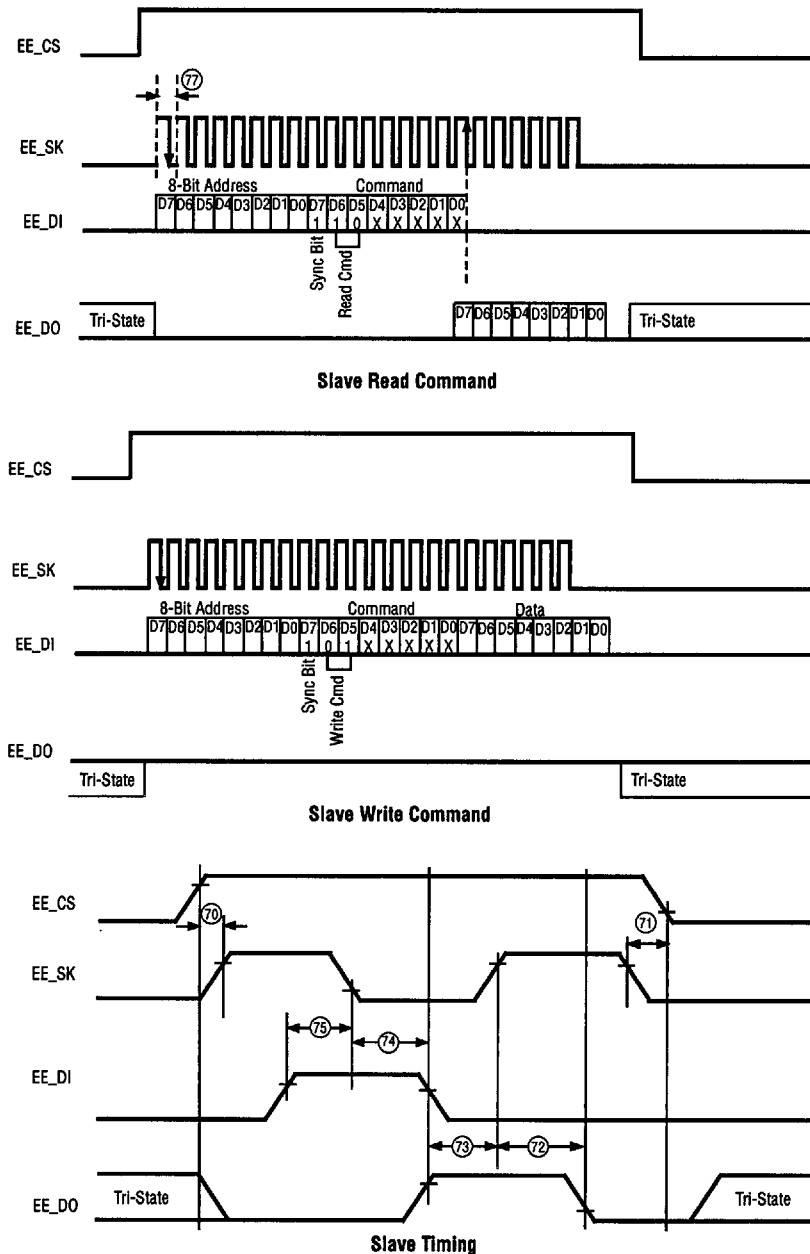


Figure B1-10. Slave Interface Timing (Read)